

| | |
|-----------|---|
| autoPROC | 1.3.0 (20200318) |
| XDS | VERSION Jan 31, 2020 BUILT=20200131 |
| AIMLESS | Version 0.7.4 |
| STARANISO | Version 2.3.33 (11-Apr-2020) |
| CCP4 | Version 7.0.078 |
| Host | server8 |
| User | vonrhein (group = users) |
| Date | Mon Apr 20 10:01:13 CEST 2020 |
| autoPROC | /home/software/xtal/GPhL/20200420 |
| m4G4eg | m4G4eg_#####.cbf (54 images, 27°) |
| m4G4eg-2 | m4G4eg-2_#####.cbf (237 images, 118.5°) |
| m4G4eg-3 | m4G4eg-3_#####.cbf (175 images, 87.5°) |
| m4G4eg-4 | m4G4eg-4_#####.cbf (107 images, 53.5°) |
| m4G4eg-5 | m4G4eg-5_#####.cbf (66 images, 33°) |

Isotropic data analysis:

| Spacegroup | P3121 | | |
|------------------------------|---|-------------|-------------|
| Cell parameters | 168.5282 168.5282 51.9549 90.0 90.0 120.0 0.97918 | | |
| Wavelength [Å] | | | |
| | Overall | Inner Shell | Outer Shell |
| Low resolution limit | 48.946 | 48.946 | 2.173 |
| High resolution limit | 2.136 | 5.796 | 2.136 |
| Rmerge (all I+ & I-) | 0.107 | 0.062 | 0.937 |
| Rmeas (all I+ & I-) | 0.111 | 0.064 | 1.003 |
| Rpim (all I+ & I-) | 0.027 | 0.016 | 0.354 |
| Total number of observations | 708930 | 41377 | 18327 |
| Total number unique | 47069 | 2462 | 2348 |
| Mean(I)/sd(I) | 20.1 | 49.9 | 2.4 |
| Completeness | 100.0 | 100.0 | 100.0 |
| Multiplicity | 15.1 | 16.8 | 7.8 |
| CC(1/2) | 0.999 | 0.999 | 0.774 |
| Anomalous completeness | 99.9 | 100.0 | 99.6 |
| Anomalous multiplicity | 7.7 | 9.0 | 4.0 |
| CC(ano) | -0.148 | -0.177 | -0.001 |
| DANO /sd(DANO) | 0.792 | 1.084 | 0.728 |

Final scaling/merging - isotropic data analysis

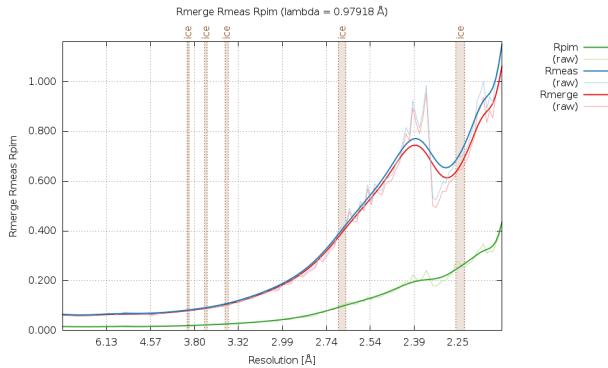


Fig.1 : R-values as a function of resolution

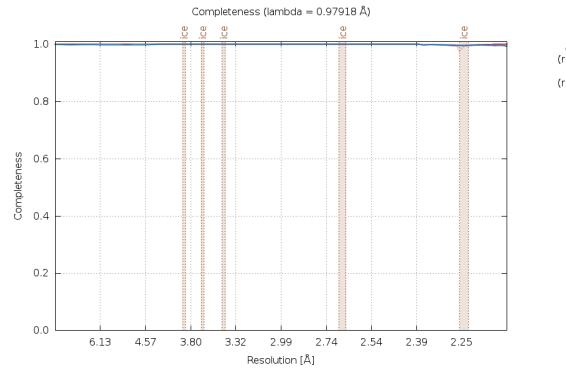


Fig.2 : Completeness as a function of resolution

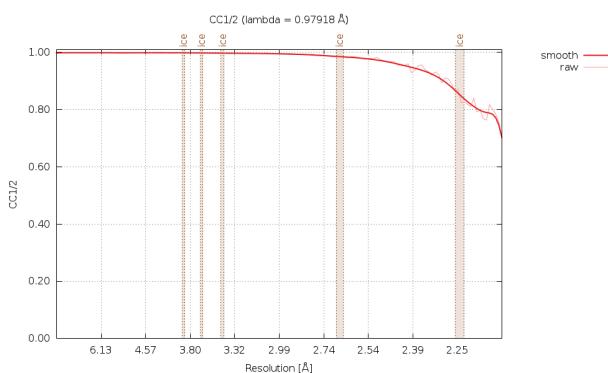


Fig.3 : CC_{1/2} as a function of resolution

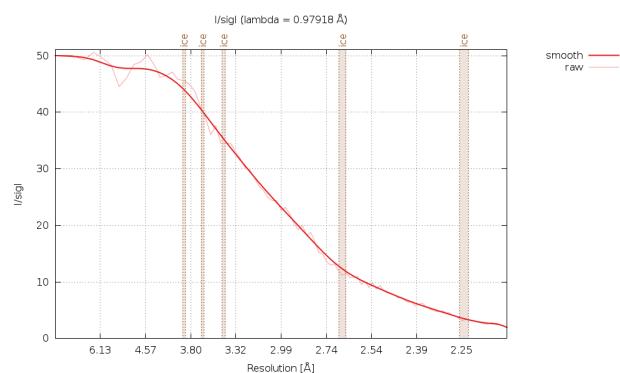


Fig.4 : I/sigl as a function of resolution

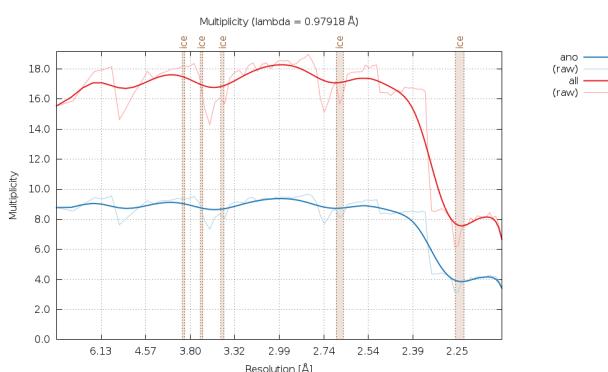


Fig.5 : Multiplicity as a function of resolution

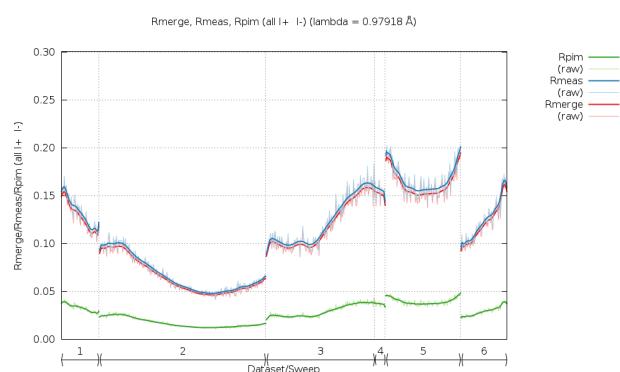


Fig.6 : R-values as a function of image number

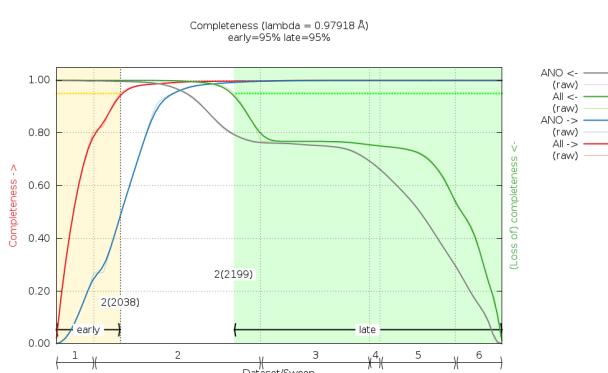


Fig.7 : Completeness as a function of image number

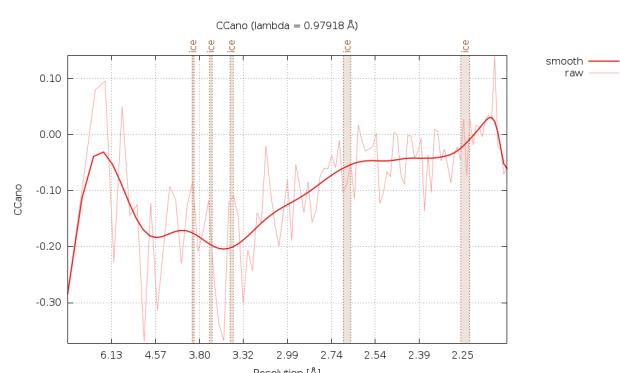


Fig.8 : CC_{ano} as a function of resolution

Final scaling/merging - isotropic data analysis

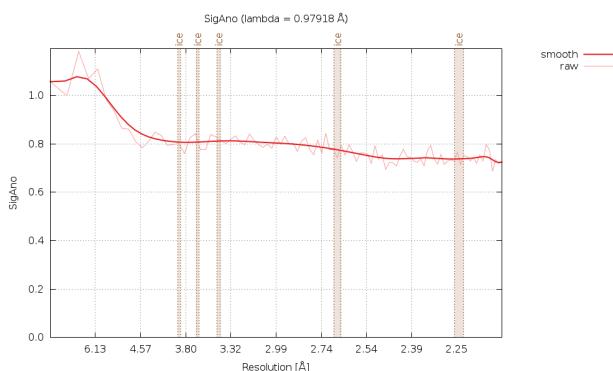


Fig.9 : SigAno as a function of resolution

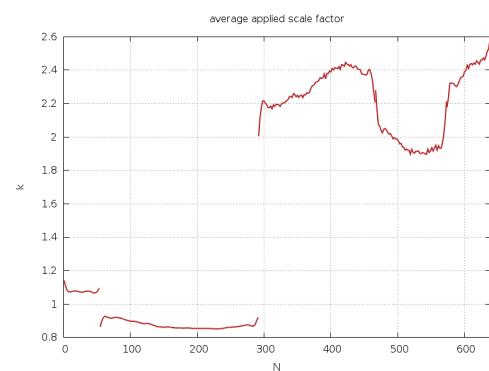


Fig.10 : Scale factor (AIMLESS scaling) as a function of image number

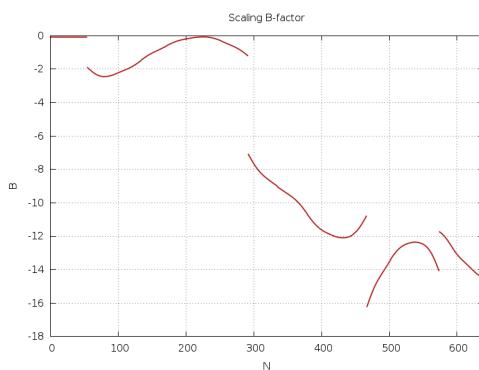


Fig.11 : Scaling B-factor (AIMLESS scaling) as a function of image number

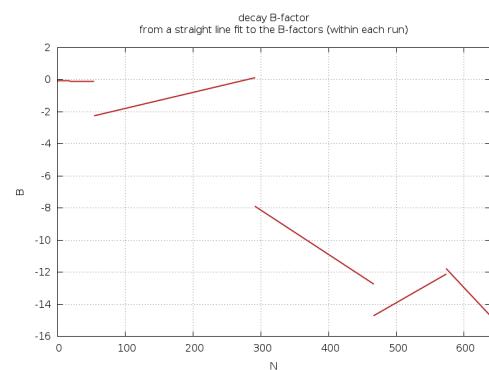


Fig.12 : Decay B-factor (AIMLESS scaling) as a function of image number

Data processing sweep m4G4eg

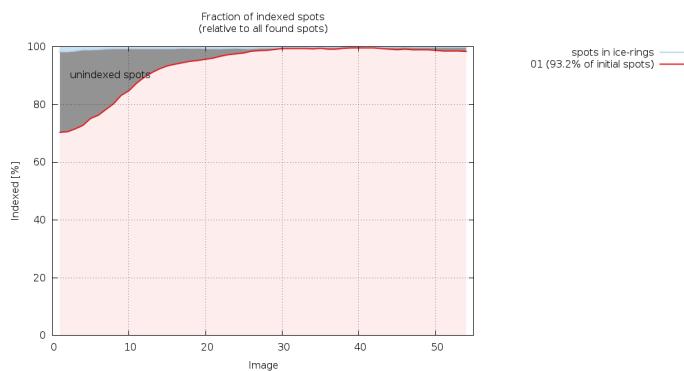


Fig.13 : (sweep m4G4eg) number of spots for each indexing solution as a function of image number

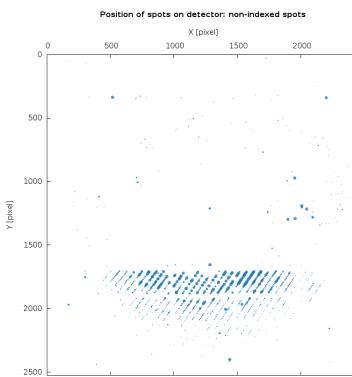


Fig.14 : (sweep m4G4eg) unindexed spots as a function of detector position

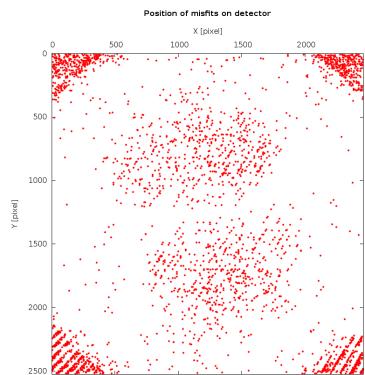


Fig.15 : (sweep m4G4eg) reflections classified as misfits (as a function of detector position)

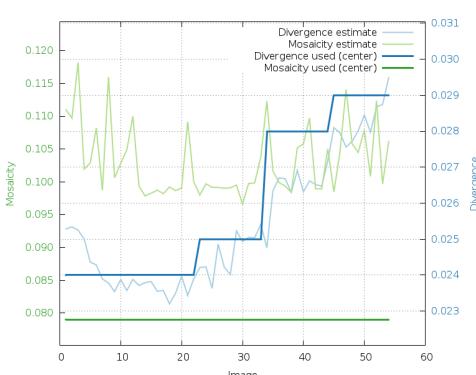


Fig.16 : (sweep m4G4eg) divergence and mosaicity (estimated and used) as a function of image number

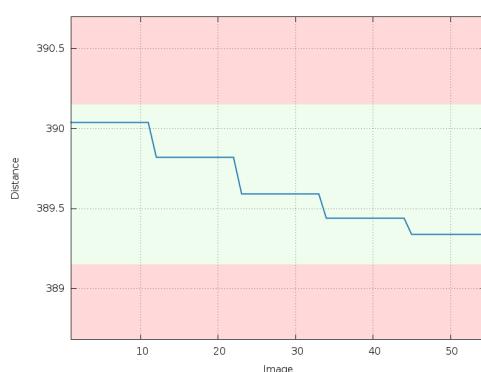


Fig.17 : (sweep m4G4eg) refined crystal-to-detector distance as a function of image number

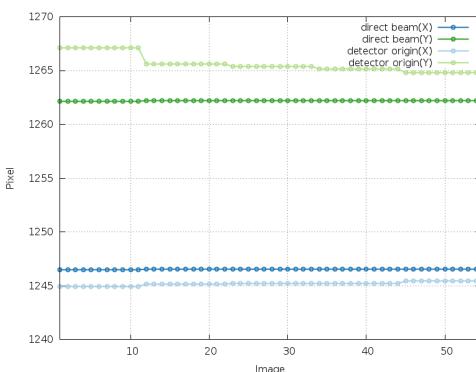


Fig.18 : (sweep m4G4eg) direct beam position and detector origin as a function of image number

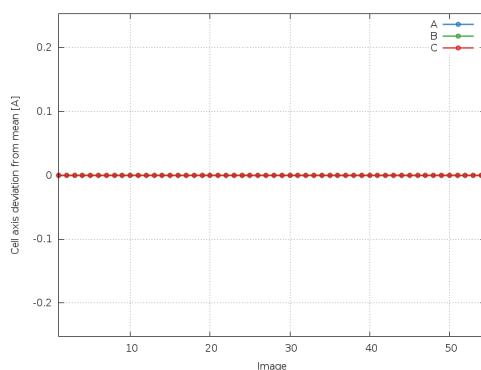


Fig.19 : (sweep m4G4eg) deviation of refined cell axes relative to their mean (as a function of image number)

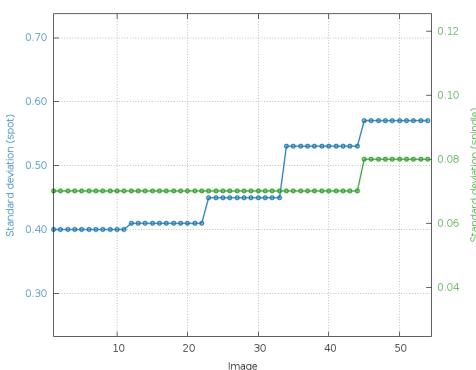


Fig.20 : (sweep m4G4eg) standard deviation (spot position and spindle) as a function of image number

Data processing sweep m4G4eg-2

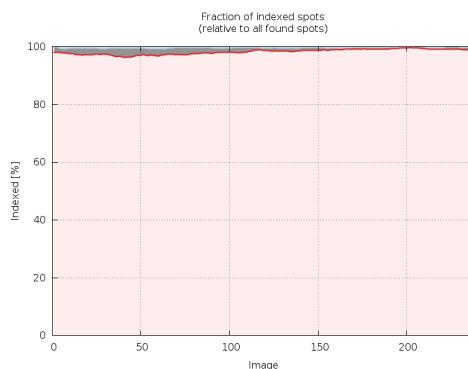


Fig.21 : (sweep m4G4eg-2) number of spots for each indexing solution as a function of image number

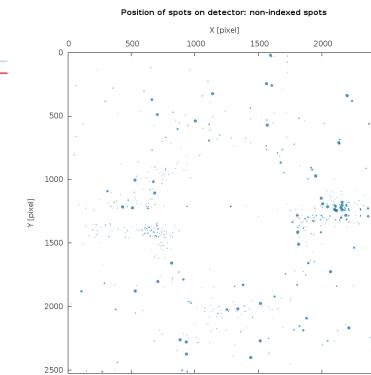


Fig.22 : (sweep m4G4eg-2) unindexed spots as a function of detector position

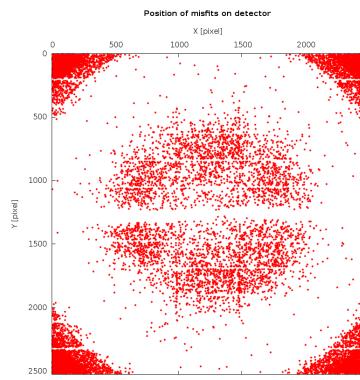


Fig.23 : (sweep m4G4eg-2) reflections classified as misfits (as a function of detector position)

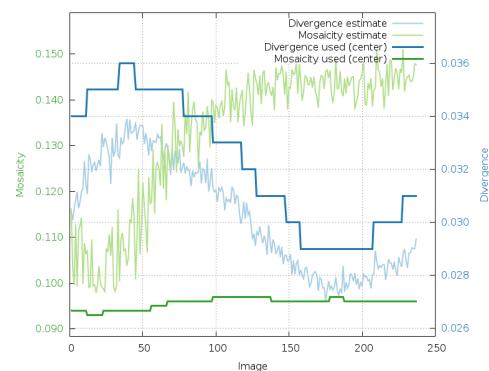


Fig.24 : (sweep m4G4eg-2) divergence and mosaicity (estimated and used) as a function of image number

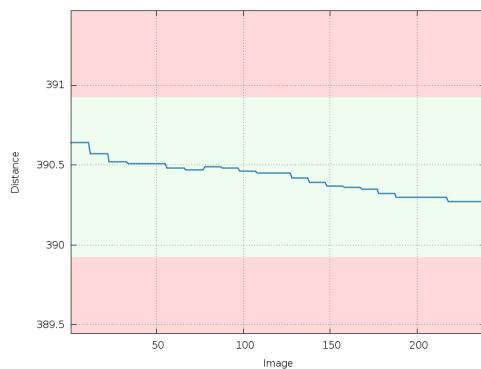


Fig.25 : (sweep m4G4eg-2) refined crystal-to-detector distance as a function of image number

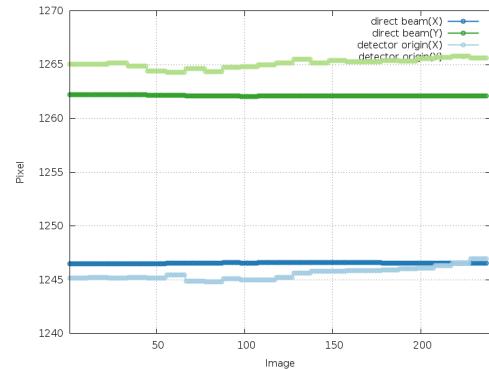


Fig.26 : (sweep m4G4eg-2) direct beam position and detector origin as a function of image number

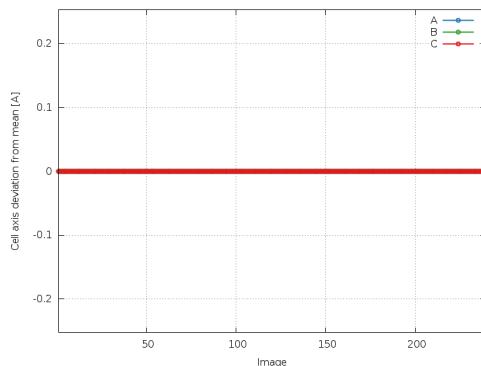


Fig.27 : (sweep m4G4eg-2) deviation of refined cell axes relative to their mean (as a function of image number)

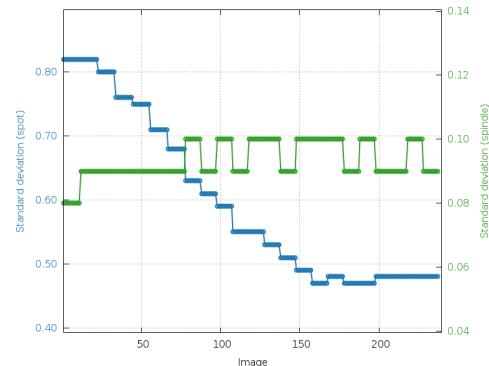


Fig.28 : (sweep m4G4eg-2) standard deviation (spot position and spindle) as a function of image number

Data processing sweep m4G4eg-3

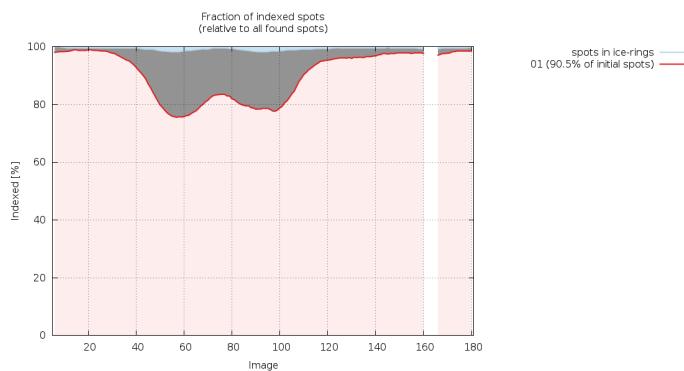


Fig.29 : (sweep m4G4eg-3) number of spots for each indexing solution as a function of image number

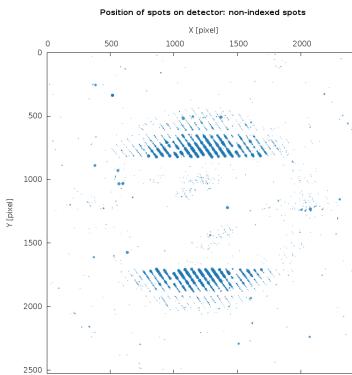


Fig.30 : (sweep m4G4eg-3) unindexed spots as a function of detector position

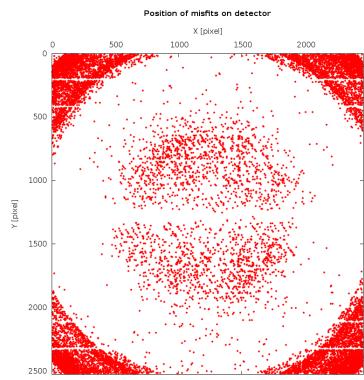


Fig.31 : (sweep m4G4eg-3) reflections classified as misfits (as a function of detector position)

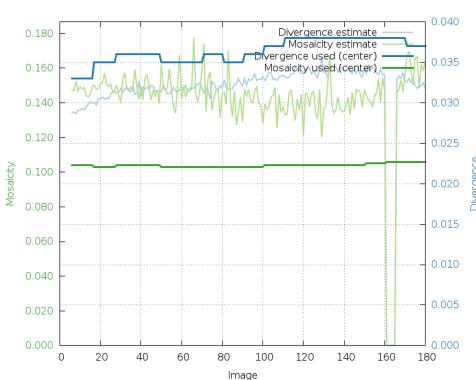


Fig.32 : (sweep m4G4eg-3) divergence and mosaicity (estimated and used) as a function of image number

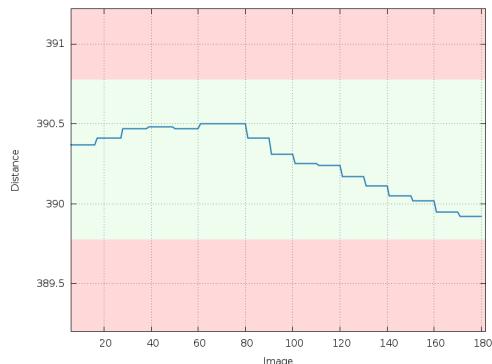


Fig.33 : (sweep m4G4eg-3) refined crystal-to-detector distance as a function of image number

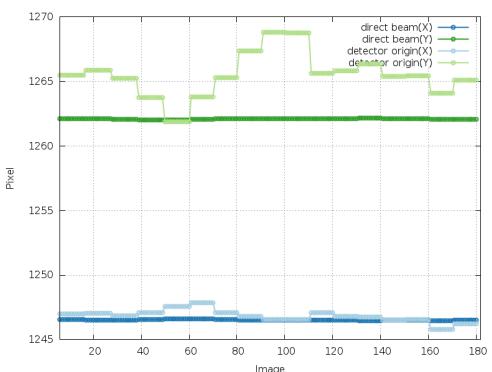


Fig.34 : (sweep m4G4eg-3) direct beam position and detector origin as a function of image number

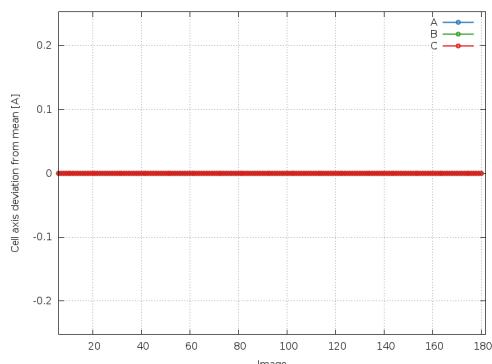


Fig.35 : (sweep m4G4eg-3) deviation of refined cell axes relative to their mean (as a function of image number)

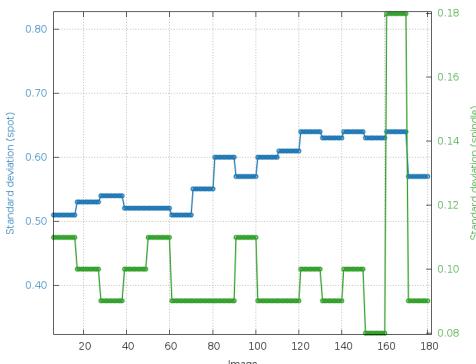


Fig.36 : (sweep m4G4eg-3) standard deviation (spot position and spindle) as a function of image number

Data processing sweep m4G4eg-4

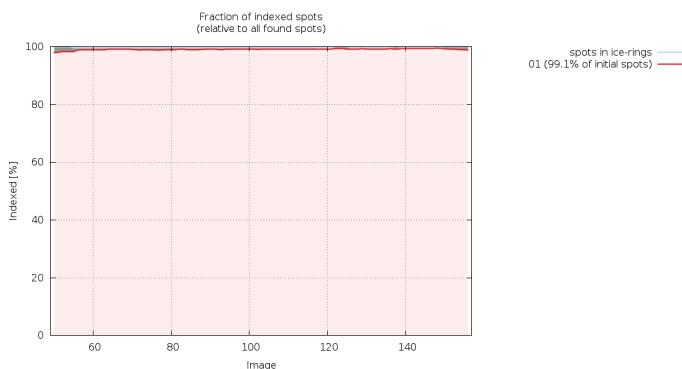


Fig.37 : (sweep m4G4eg-4) number of spots for each indexing solution as a function of image number

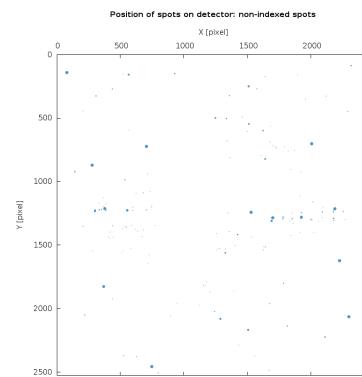


Fig.38 : (sweep m4G4eg-4) unindexed spots as a function of detector position

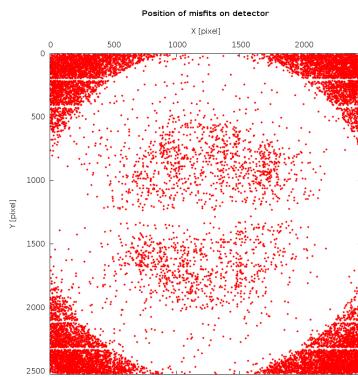


Fig.39 : (sweep m4G4eg-4) reflections classified as misfits (as a function of detector position)

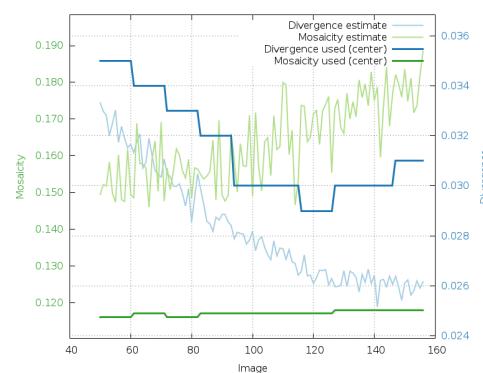


Fig.40 : (sweep m4G4eg-4) divergence and mosaicity (estimated and used) as a function of image number

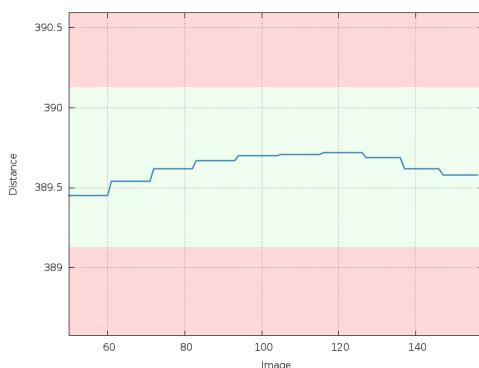


Fig.41 : (sweep m4G4eg-4) refined crystal-to-detector distance as a function of image number

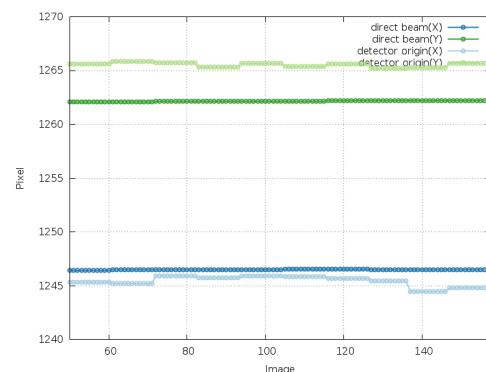


Fig.42 : (sweep m4G4eg-4) direct beam position and detector origin as a function of image number

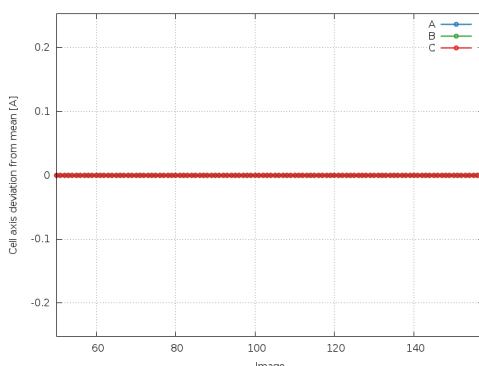


Fig.43 : (sweep m4G4eg-4) deviation of refined cell axes relative to their mean (as a function of image number)

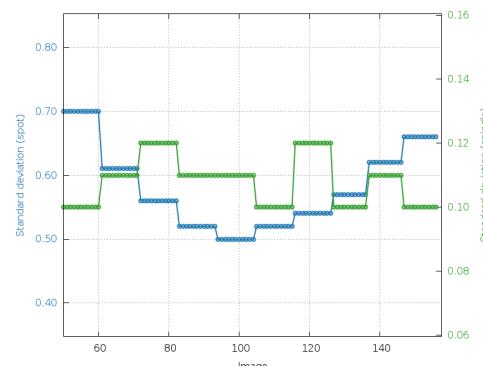


Fig.44 : (sweep m4G4eg-4) standard deviation (spot position and spindle) as a function of image number

Data processing sweep m4G4eg-5

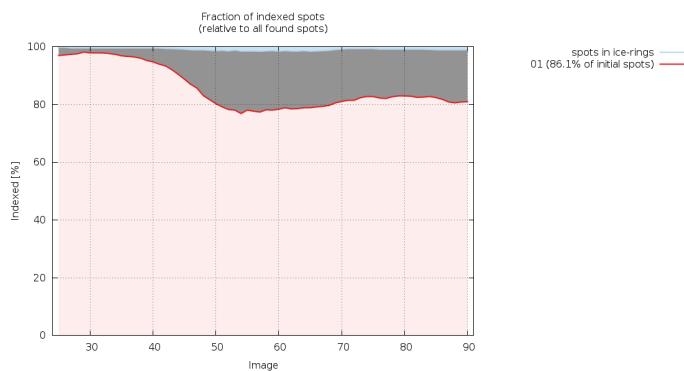


Fig.45 : (sweep m4G4eg-5) number of spots for each indexing solution as a function of image number

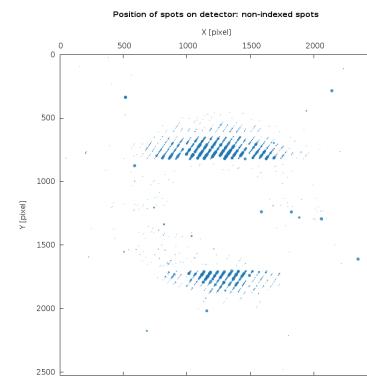


Fig.46 : (sweep m4G4eg-5) unindexed spots as a function of detector position

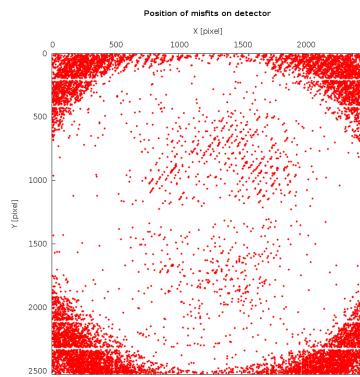


Fig.47 : (sweep m4G4eg-5) reflections classified as misfits (as a function of detector position)

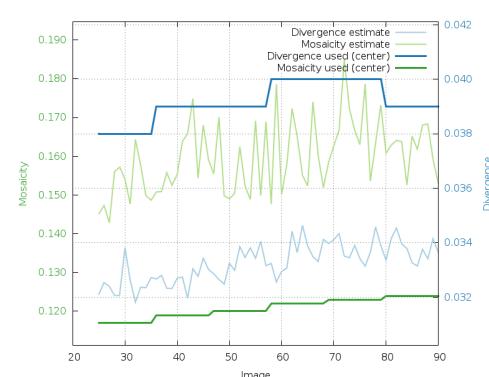


Fig.48 : (sweep m4G4eg-5) divergence and mosaicity (estimated and used) as a function of image number

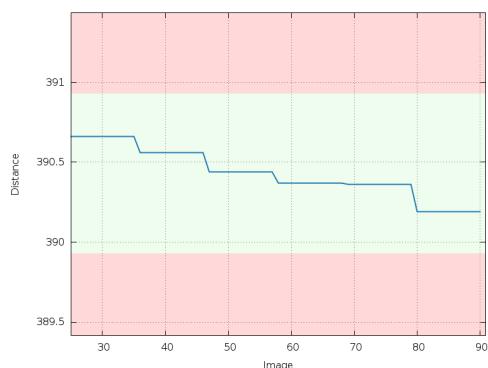


Fig.49 : (sweep m4G4eg-5) refined crystal-to-detector distance as a function of image number

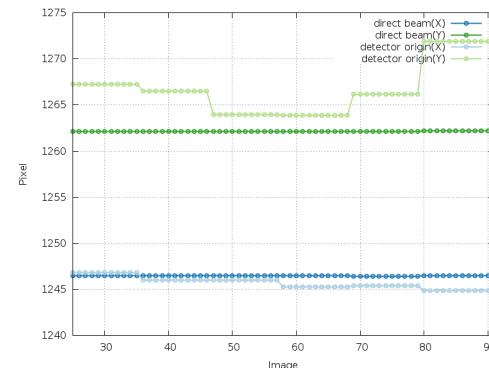


Fig.50 : (sweep m4G4eg-5) direct beam position and detector origin as a function of image number

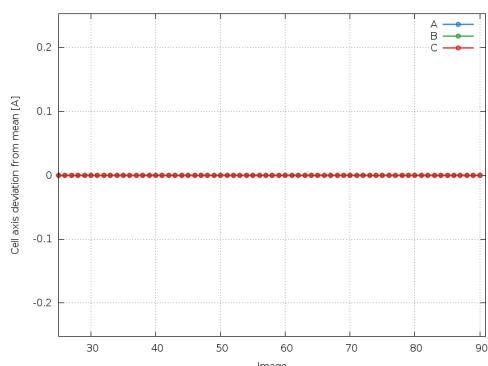


Fig.51 : (sweep m4G4eg-5) deviation of refined cell axes relative to their mean (as a function of image number)

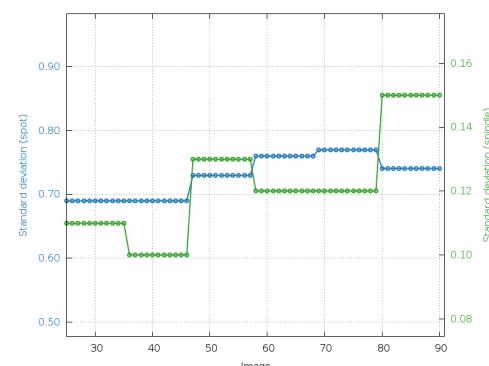


Fig.52 : (sweep m4G4eg-5) standard deviation (spot position and spindle) as a function of image number

References

- autoPROC Vonrhein, C., Flensburg, C., Keller, P., Sharff, A., Smart, O., Paciorek, W., Womack, T. and Bricogne, G. (2011). Data processing and analysis with the autoPROC toolbox. *Acta Cryst. D67*, 293-302.
- XDS Kabsch, W. (2010). XDS. *Acta Cryst. D66*, 125-132.
- POINTLESS Evans, P.R. (2006). Scaling and assessment of data quality, *Acta Cryst. D62*, 72-82.
- AIMLESS Evans, P.R. and Murshudov, G.N. (2013). How good are my data and what is the resolution?, *Acta Cryst. D69*, 1204-1214.
- CCP4 Winn, M.D., Ballard, C.C., Cowtan, K.D. Dodson, E.J., Emsley, P., Evans, P.R., Keegan, R.M., Krissinel, E.B., Leslie, A.G.W., McCoy, A., McNicholas, S.J., Murshudov, G.N., Pannu, N.S., Potterton, E.A., Powell, H.R., Read, R.J., Vagin, A. and Wilson, K.S. (2011). Overview of the CCP4 suite and current developments, *Acta Cryst. D67*, 235-242.
- STARANISO Tickle, I.J., Flensburg, C., Keller, P., Paciorek, W., Sharff, A., Vonrhein, C., and Bricogne, G. (2020). STARANISO. Cambridge, United Kingdom: Global Phasing Ltd.